

CRC

Beam lines and access

CMS upgrade meeting

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UCLouvain

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CRC facilities at Louvain-la-Neuve

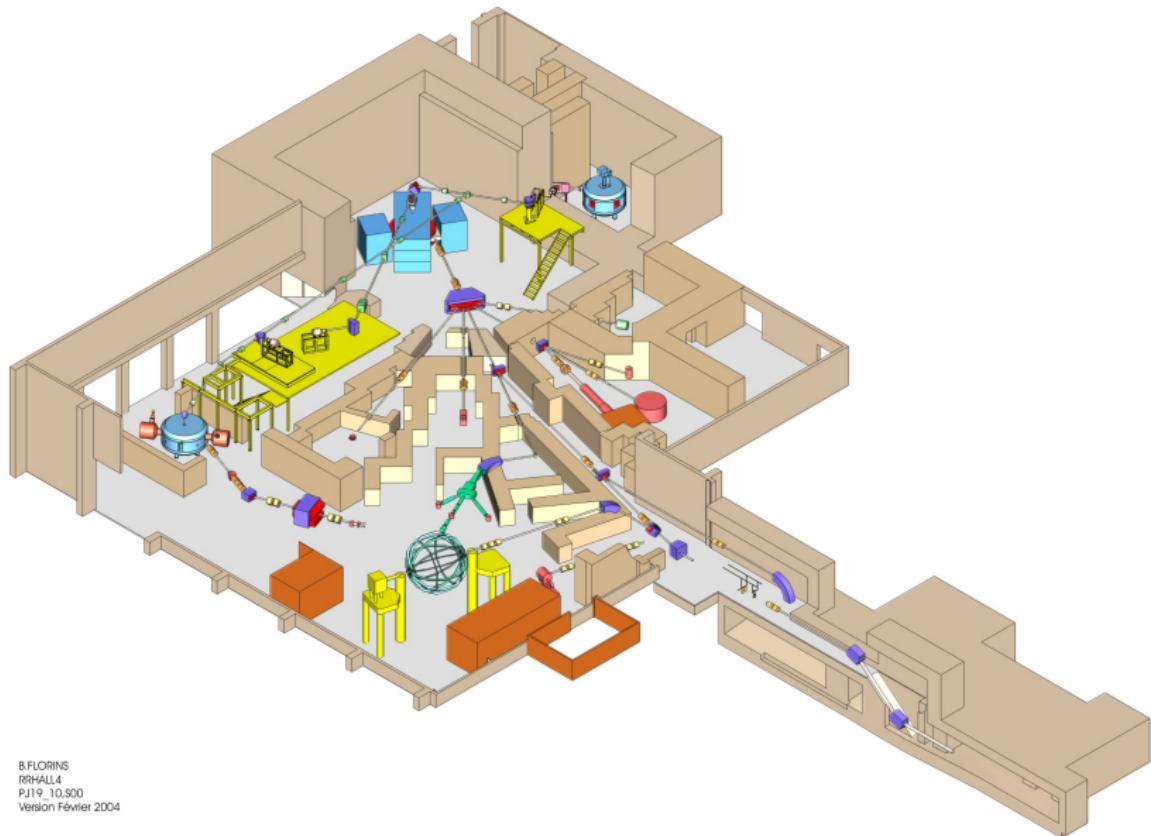
Located at Louvain-la-Neuve (~20 km from Brussels)

Institut de Recherche en Mathématique et Physique (IRMP)
Center for Cosmology, Particle Physics and Phenomenology (CP3)
Centre de Ressources du Cyclotron (CRC)

Three irradiation facilities

- NIF: Neutron Irradiation Facility
 - ▶ Fast Neutrons (0-50 MeV)
 - ▶ Flux: $10^{11} n/(cm^2 s)$
- LIF: Proton Irradiation Facility
 - ▶ Protons 10-60 MeV
 - ▶ Flux: $5 \times 10^8 p/(cm^2 s)$
- HIF: Heavy-Ion Irradiation Facility
 - ▶ Heavy Ion "cocktails"
 - ▶ Electronic failures induced by radiation

CRC facilities at Louvain-la-Neuve



B.FLORINS
RHALL4
PJ19_10.500
Version Février 2004

1. HIF: Heavy Ion Facility

HIF: Heavy Ion Facility

Facility to measure the response of electronic components to single event effects (SEE).



Single Event Effects

SEE: Effects caused by a single energetic particle. Depends on energy released (LET)

Non-destructive effects (Soft errors)

SET: Single Event Transient

SEU: Single Event Upset

SBU: Single Bit Upset

MBU: Multiple Bit Upset

SEFI: Single Event Functional Interruption

SEL: Single Event Latchup

Destructive effects (Hard errors)

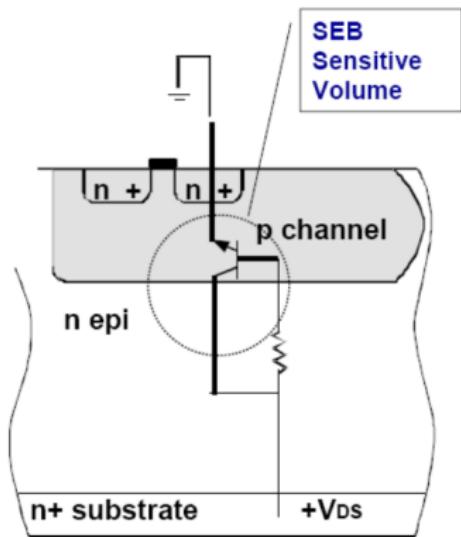
SHE: Single Hard Error (bit stuck)

SEL: Single Event Latchup

SEB: Single Event Burnout

SEGR: Single Event Gate Rupture

SEDR: Single Event Dielectric Rupture



How to measure SEE

$$\frac{G}{\Phi} = \frac{N_{SEE}}{\Phi}$$

← Number of SEE
 ← Fluence $\frac{\text{ions}}{\text{cm}^2}$ $\rightarrow \Phi: 1 - 10^4 \text{ ions/cm}^2 \rightarrow \text{dead time}$
 $\Phi \uparrow \rightarrow \text{better statistical error}$
 $\rightarrow \text{Total Dose effects}$

Weibull function

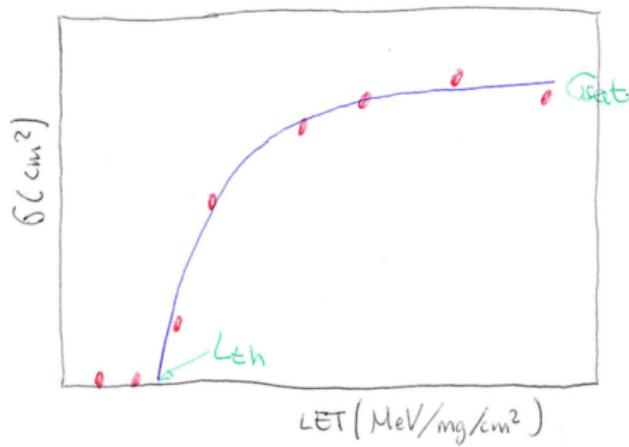
$$G = G_{sat} \left(1 - e^{-\left(\frac{L-L_{th}}{w}\right)^s} \right)$$

G_{sat} : Saturation Cross-section

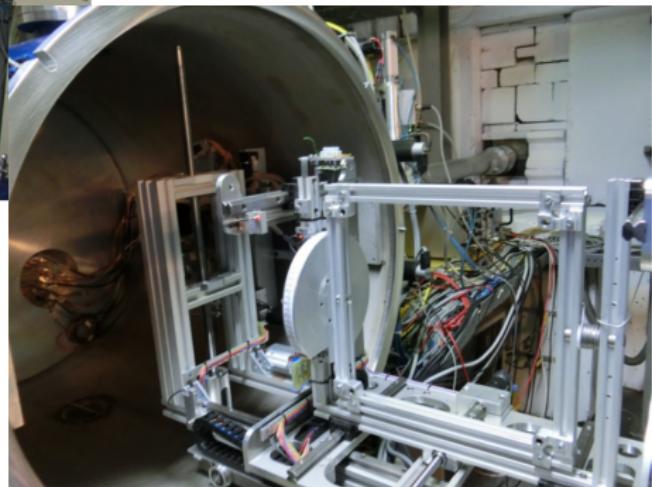
L_{th} : Threshold value

$$L < \rightarrow G = 0$$

w, s : fit parameters



HIF facility: the pictures



HIF characteristics

- Two heavy ions **cocktails** covering a wide range of LET and ranges.
 - ▶ Fully characterisation of SEE response of electronic components.
 - ▶ Fast ion changing within the same cocktail (few minutes)
- Beam flux is variable between a few ions/s.cm² and $\sim 10^4$ ions/s.cm²
 - ▶ Can be modified from user **station**
 - ▶ Online monitoring → high precision in fluence delivered
- Several and redundant **metrology**
 - ▶ Fluence and energy
 - ▶ Moving frame, alignment system
 - ▶ ESA SEU monitor: 4x4 Mbit SRAM (Atmel AT60142F) arranged in a square region of 24mm x 24mm
- Beam homogeneity of 10% on a 25 mm diameter.
- Standard mechanical interface and feedthroughs
- Irradiations are done in vacuum and for most of the ions naked chips are needed.

next

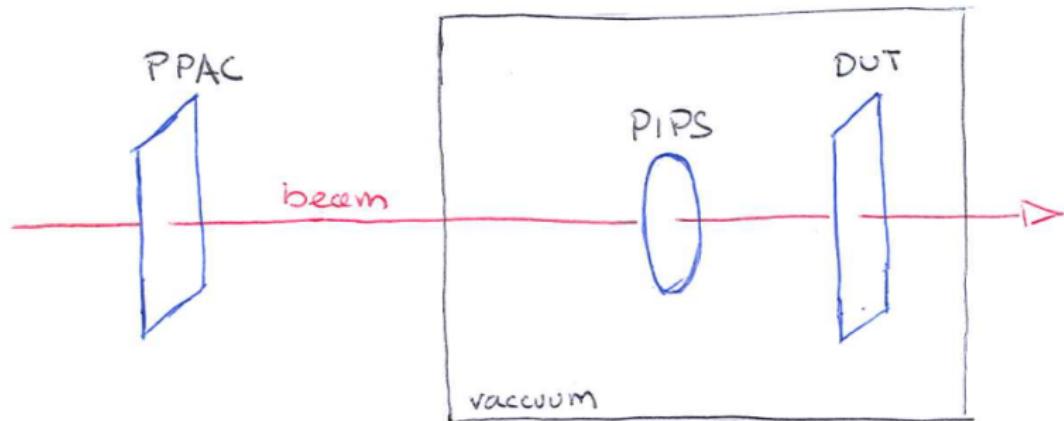
HIF "cocktails"

	M/Q	Ion	DUT energy [MeV]	Range [μm Si]	LET [MeV/mg/cm ²]
Cocktail 1 High LET	5	¹⁵ N ³⁺	60	59	3.3
	5	²⁰ Ne ⁴⁺	78	45	6.4
	5	⁴⁰ Ar ⁸⁺	151	40	15.9
	4.94	⁸⁴ Kr ¹⁷⁺	305	39	40.4
	4.96	¹²⁴ Xe ²⁵⁺	420	37	67.7
Cocktail 2 High penetration	3.25	¹³ C ⁴⁺	131	292	1.1
	3.14	²² Ne ⁷⁺	235	216	3
	3.33	⁴⁰ Ar ¹²⁺	372	117	10.2
	3.22	⁵⁸ Ni ¹⁸⁺	567	100	20.4
	3.32	⁸³ Kr ²⁵⁺	756	92	32.6
	3.54	¹²⁴ Xe ³⁵⁺	995	73	62.5

Quality assurance

For each run/cocktail a whole calibration and quality assurance procedure is performed.

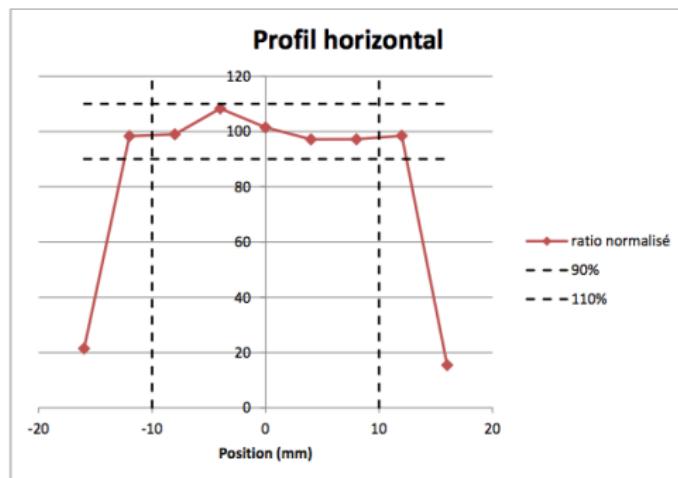
1. Fluence: PPAC+PIPS
2. Profile: PIPS+SEU monitor
3. Energy: PIPS



QA: Beam profile and beam energy

1) Horizontal profile

Reference beam :	$^{40}\text{Ar}^{8+}$ 151MeV
Horizontal homogeneity :	24 mm
Minimum X value(mm) :	-12 mm
Maximum X value (mm) :	+12 mm



Cocktail	Particle	Energy DUT (MeV)	Measured energy (MeV)
M/Q = 5	$^{15}\text{N}^{3+}$	60	60
	$^{20}\text{Ne}^{4+}$	78	76
	$^{40}\text{Ar}^{8+}$	151	144
	$^{84}\text{Kr}^{17+}$	305	290
	$^{124}\text{Xe}^{25+}$	420	410

QA: SEU monitor

540	518	530	539	552	538
538	517	583	535	539	508
562	530	520	534	557	523
521	532	523	568	525	549
517	494	536	508	535	553
510	539	567	541	538	552
560	560	503	529	540	557
554	540	509	543	549	576
540	561	537	563		
539	575	606	562		
512	536	551	601		
582	523	559	568		
585	576	583	543		
554	532	529	566		
536	528	509	567		
545	585	589	614		

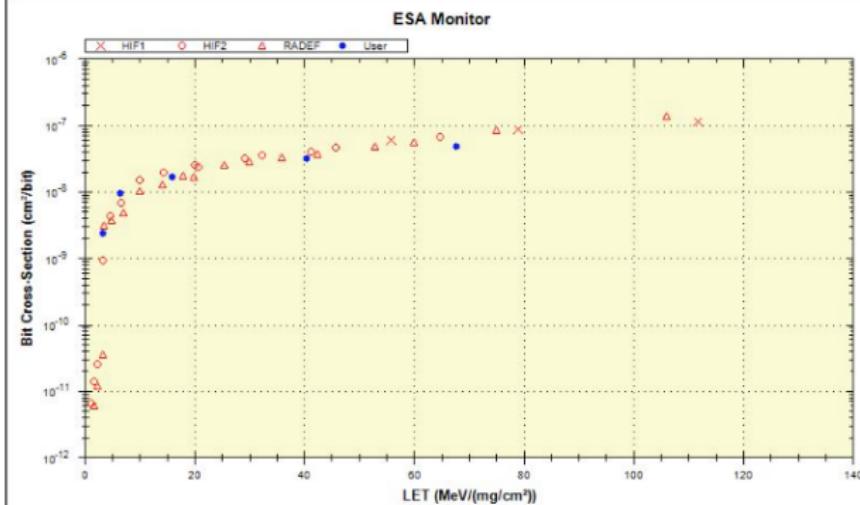
DIE 0

540	555	525	568	501	498
562	548	540	511	521	548
573	563	583	572	552	482
538	525	541	514	528	539
548	554	562	569	519	520
588	482	545	544	524	548
570	549	567	513	533	552
535	561	559	537	527	510
545	569	598	492		
579	669	549			
527	551	596	553		
560	571	533	552		
551	516	555	533		
524	526	491	546		
525	534	532	556		
541	537	535	513		
575	592	534	557	499	
538	547	527	542	557	487
531	516	542	529	538	542
514	560	533	548	522	541
535	530	536	522	541	544
559	524	502	552	495	496
526	497	526	484	526	524

DIE 2

DIE 1

Moyenne	535
110%	589
90%	482

Courbe des sections efficace $\sigma_{(LET)}$ 

return

User station control panel

BEAM ON / OFF

Time Stamp
12:55:37
14/01/2015

User

VS PIPS call PIPS scan HOME X PIPS scan HOME Y Faraday local

PPAC (part/s)
11863

Normal Flux [part/s cm⁻²]
2673

Device flux [part/s cm⁻²]
2673

Desired fluence [part/cm⁻²]
50000

Elapsed Time (sec)
5

Estimated Remaining Time (sec)
0

CF1 out run number
tilt angle
40 0 25 50 75 90

Ion Kr-305

Energy [MeV] 305 Range [μm S] 39

LET [MeV/mg/cm²] 40.4 LETeff [MeV/mg/cm²] 40.4

Mean Device flux Run Dose [Rad] 14.5 2671

Remaining Fluence [%]

Reached Fluence [part/cm⁻²]
13358

Remaining Fluence [part/cm⁻²]
39315

intermeasure time (sec)
1

Device Flux

save now

Time Device Flux

2. NIF: Neutron Irradiation Facility

NIF: Neutron Irradiation Facility

Bulk damage in materials.

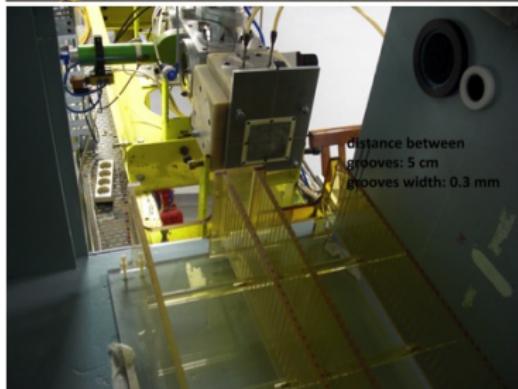
- 50 MeV deuterons on Be target:
- $I_d \sim \mu A$
- Filters for γ and low energy neutrons
 - ▶ 10 mm polyethylene
 - ▶ 1 mm cadmium
 - ▶ 1 mm lead
- Cool box (down to -25 C)

d(cm)	R(cm)	t(h)
5	2	1.6
20	5	24
40	8	88

d : distance to target

R : Radius (80% neutrons)

t : time for $\Phi = 10^{14} \text{ n/cm}^2$ ($I_d = 1\mu A$)



Neutron Energy

- Continuous spectra
- Low energy neutrons removed
- MPV = 23 MeV
- Maximum neutron energy 50 MeV

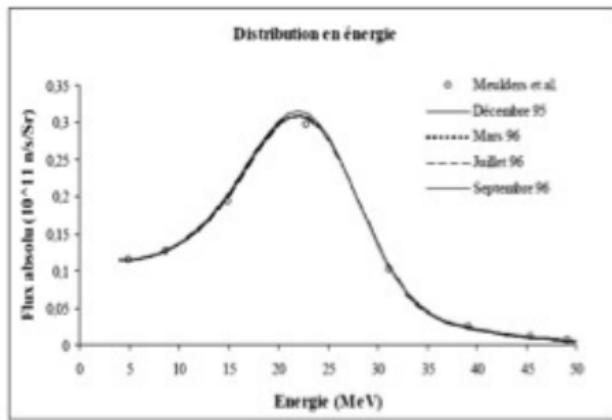


Figure 3.12 : Comparaison des résultats de “déconvolution” ajustés par une fonction « spline » avec quelques points mesurés par Meuldres et al. [42].

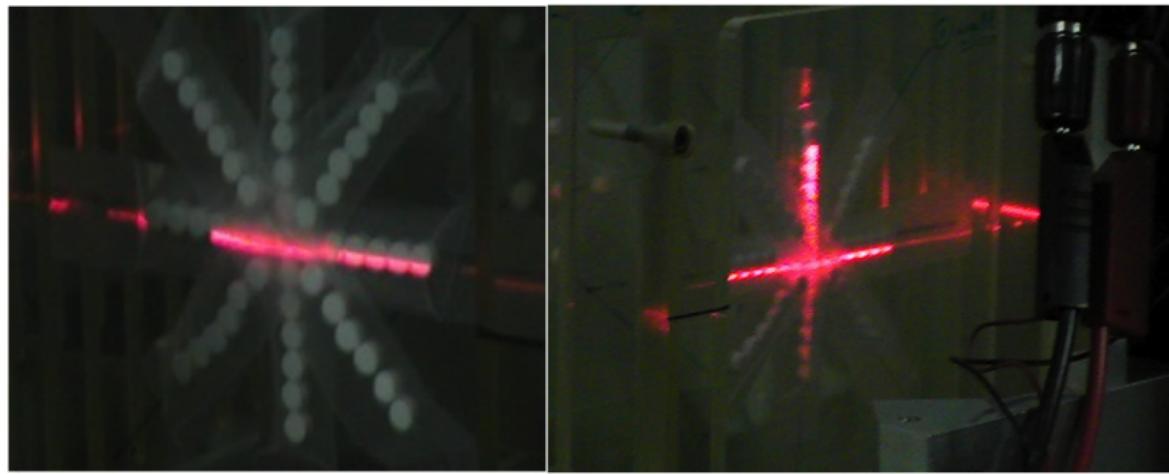
Fluence control

- Deuterons current measured continuously.

$$\Phi(\text{n/cm}^2) = 10^{14} \frac{I(\mu\text{A}) t(\text{h})}{0.079 r^{1.902}}$$

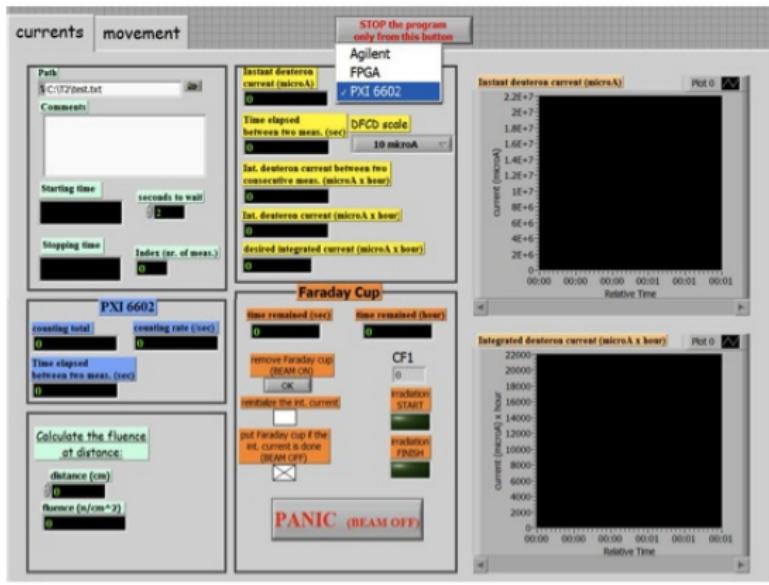
- Alanine dosimeters: present in all irradiations

$$D(\text{Gy}) = \Phi \times K \quad K=4.16 \text{ fGy m}^2$$



NIF control

- Control fully automated
 - Instantaneous and integrated current
 - Beam control
 - Box temperature and movement



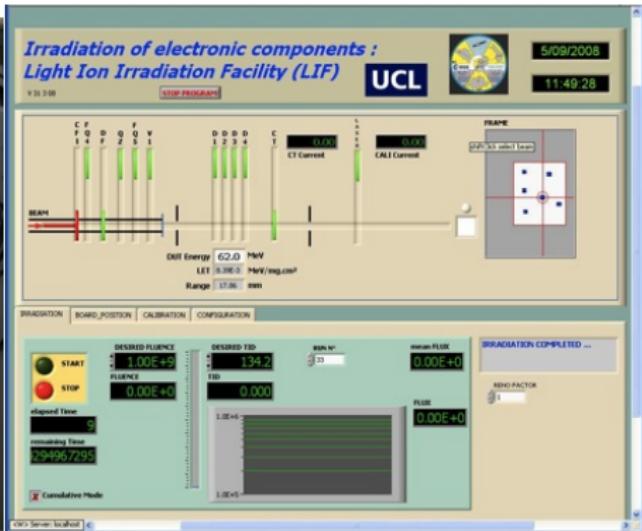
3. LIF: Proton Irradiation Facility

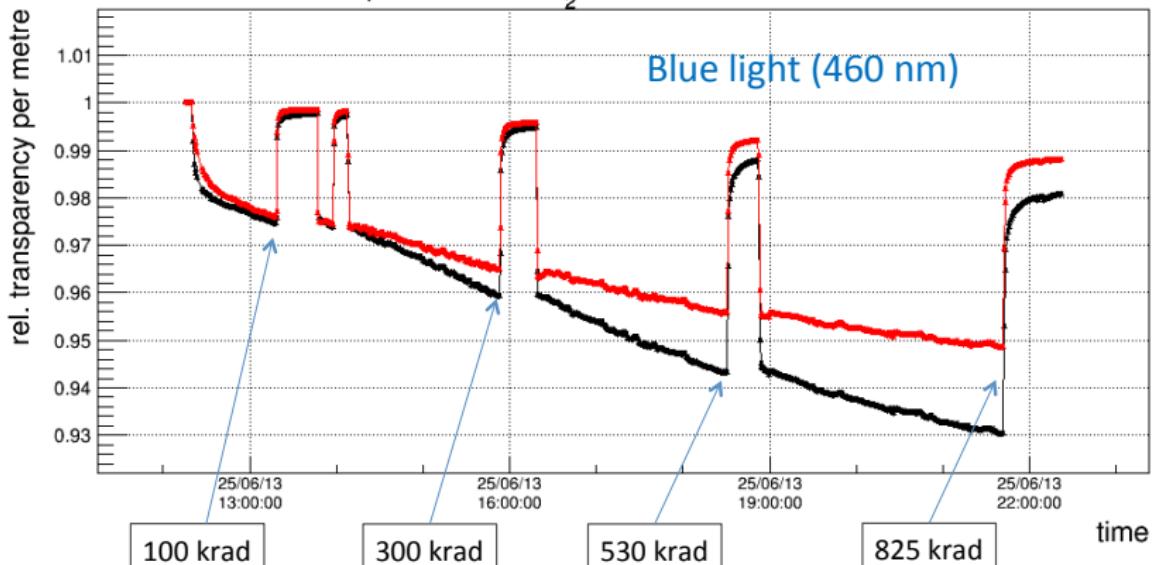
LIF: Proton Irradiation Facility

- Protons 62 MeV + Energy degraders (Polystyrene blocks)
- Max Flux: $10^9 p/(cm^2 s)$
- Homogeneity: $\pm 10\%$ on a diameter of 8 cm
- Spot size: collimator from 1-8 cm
- Dosimetry:
 - ▶ Profile: Water Phantom + diodes
 - ▶ Flux: Ionization chamber
 - ▶ Energy: Faraday cup + SEU monitor from ESA



Energy degraders and control



I_1 (black) Rus, I_2 (red) Polymicro

Tested were two types of pure silica-high OH quartz fibers with 200 μ core, produced by Polymicro (USA) and Fryazino (Russia). Both found to be good enough for the upgrade of LHCb ECAL calibration system.

Transparency loss measured after short (20-30 min) annealing, for LHCb dose rates (< 0.01 rad/s) can be considered as an upper limit.

dose, krad	transparency loss, % / m	
	Polymicro	Rus
100	0.14	0.23
300	0.45	0.54
530	0.8	1.2
825	1.2	1.9

Access to CRC

- CRC runs from March to December (2-3 weeks break in summer)
 - ▶ HIF 2/3 weeks/month
 - ▶ LIF,NIF 1-2 days/month
- Access cost:
 - ~ 750 EUR/h (for all facilities)
 - ~ 400 EUR/h (for belgian universities)
 - "Free" for AIDA2020 (belgian institutes not eligible)
 - "Free" for UCL users
- Contact persons:
 - Nancy.Postiau@uclouvain.be
 - Eduardo.Cortina@uclouvain.be (for AIDA2020)